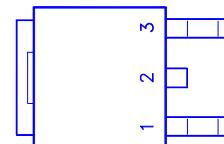
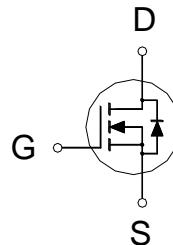


**NIKO-SEM**
**N-Channel Enhancement Mode  
Field Effect Transistor**
**P3606BD**  
**TO-252**  
**Halogen-Free & Lead-Free**
**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
60V	36mΩ	22A

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		$V_{DS}$	60	V
Gate-Source Voltage		$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	$I_D$	22	A
	$T_C = 100^\circ\text{C}$		14	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	45	A
Avalanche Current		$I_{AS}$	18	
Avalanche Energy	$L = 0.1\text{mH}$	$E_{AS}$	16	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	$P_D$	39	W
	$T_C = 100^\circ\text{C}$		15.6	
Junction & Storage Temperature Range		$T_J, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		3.2	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	

<sup>1</sup>Pulse width limited by maximum junction temperature.
**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.3	1.8	2.3	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 48\text{V}, V_{GS} = 0\text{V}$			1	$\mu\text{A}$
		$V_{DS} = 40\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(\text{ON})}$	$V_{GS} = 4.5\text{V}, I_D = 15\text{A}$		34	47	$\text{m}\Omega$
		$V_{GS} = 10\text{V}, I_D = 20\text{A}$		31	36	

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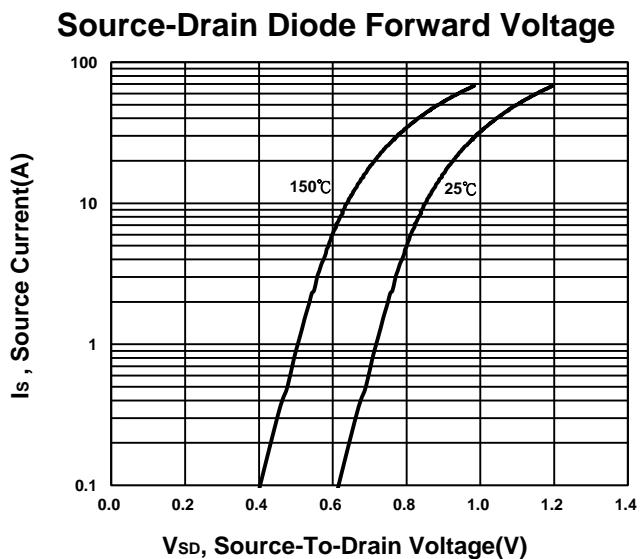
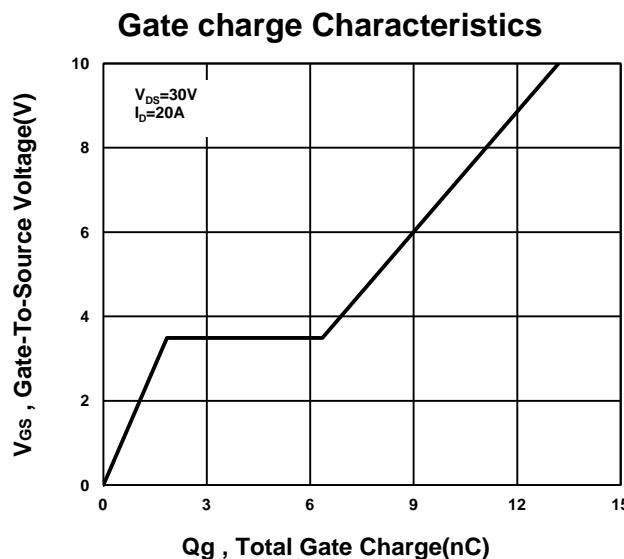
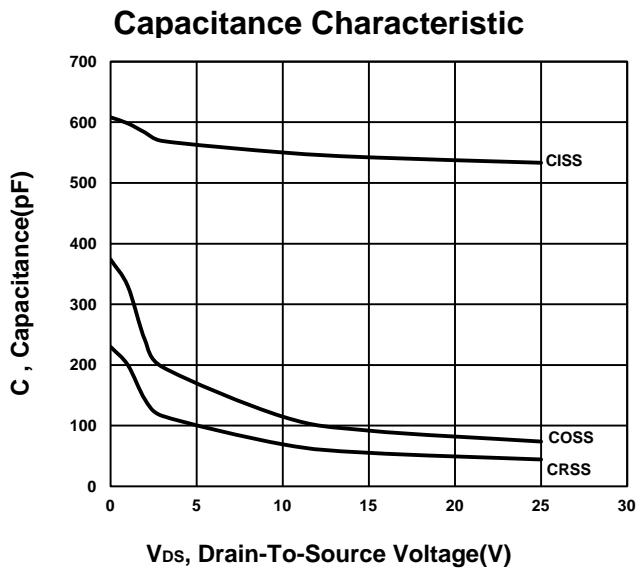
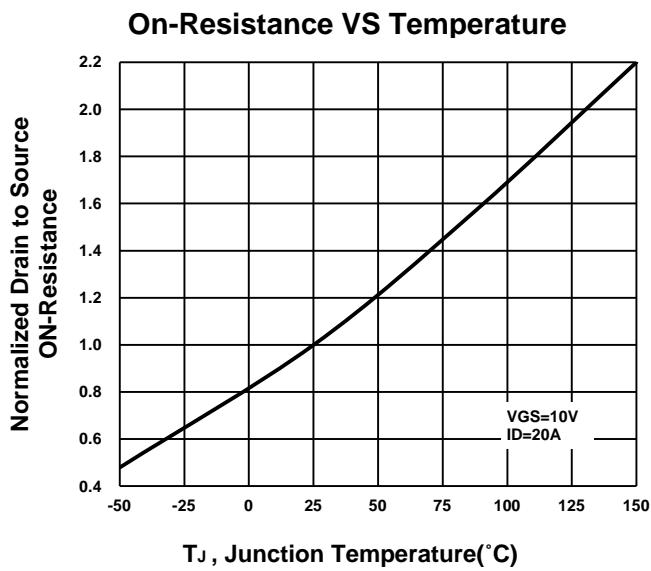
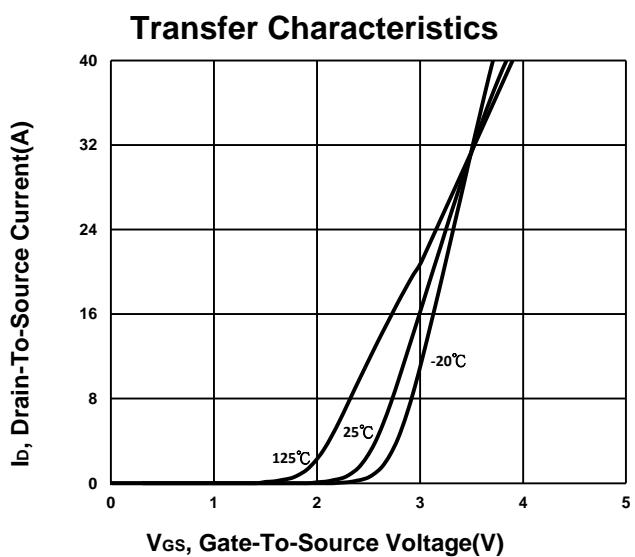
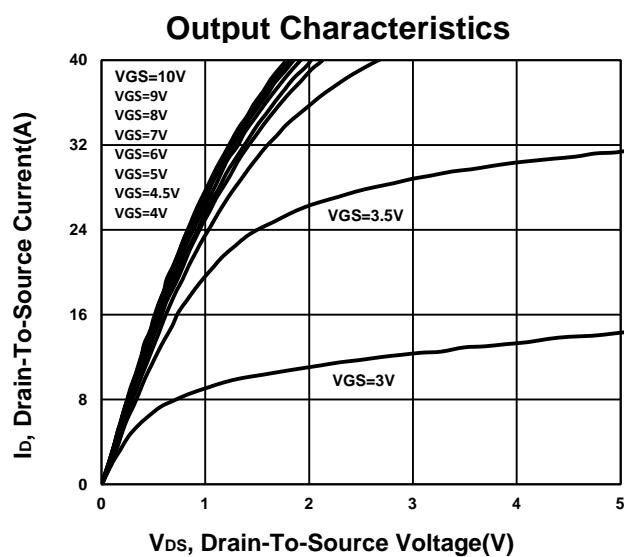
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 5V, I_D = 20A$		30		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		545		pF
Output Capacitance	$C_{oss}$			74		
Reverse Transfer Capacitance	$C_{rss}$			44		
Gate Resistance	$R_g$		$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$	1.8		$\Omega$
Total Gate Charge <sup>2</sup>	$Q_{g(VGS=10V)}$	$V_{DS} = 30V, I_D = 20A$		13.8		nC
	$Q_{g(VGS=4.5V)}$			7.9		
Gate-Source Charge <sup>2</sup>	$Q_{gs}$			2		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$			4.9		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	$I_D \approx 20A, V_{GS} = 10V, R_{GEN} = 6\Omega$		17		nS
Rise Time <sup>2</sup>	$t_r$			11		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$			33		
Fall Time <sup>2</sup>	$t_f$			10		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ C</math>)</b>						
Continuous Current	$I_S$				22	A
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 20A, V_{GS} = 0V$			1.3	V
Reverse Recovery Time	$t_{rr}$	$I_F = 20A, dI_F/dt = 100A / \mu S$		17.6		nS
Reverse Recovery Charge	$Q_{rr}$			8.8		nC

<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.

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